



FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
ASMEX.367AAPPLICATION NO.  
10/074,534INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT  
Michael A. ToddFILING DATE  
February 11, 2002GROUP  
2812

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	6,159,828	12/12/00	Ping et al.	438	486	
	6,171,662 B1	01/09/01	Nakao	427	595	
	6,197,669 B1	03/06/01	Twu et al.	438	585	

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

## OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

EXAMINER INITIAL	

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EXAMINER	DUPLICATE - ORIGINAL	DATE CONSIDERED	INITIALED ON 6/31/03
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

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## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

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						YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
SN	1	V. Z-Q Li <i>et al.</i> , Appl. Phys. Lett. 71(23) 3388-90 (1997)
	2	T-J King <i>et al.</i> , J. Electrochem. Soc., 141(8) 2235-41 (1994)
	3	A. Kovalgin <i>et al.</i> , ProRISC/IEEE 311-17 (1998)
	4	C. Hernandez <i>et al.</i> , Mat. Res. Soc. Symp. Proc. 533 93-98 (1998)
	5	M. Cao <i>et al.</i> , J. Electrochem. Soc., 142(5) 1566-72 (1995)
SN	6	J. Holleman <i>et al.</i> , J. Electrochem. Soc. 140(6) 1717-22 (1993)

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EXAMINER	DATE CONSIDERED
9	9/27/2004

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Michael A. Todd	
		FILING DATE February 11, 2002	GROUP 2814

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
1. <i>gh</i>	5,214,002	05/25/93	Hayashi et al.			
2. <i>1</i>	5,356,821	10/18/94	Naruse et al.			
3. <i>1</i>	5,471,330	11/28/95	Sarma			
4. <i>1</i>	6,103,600	08/15/00	Ueda et al.			
<i>gh</i>						

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
5. <i>gh</i>	11317530	16-11-99	Japan (abstract)			X	
6. <i>1</i>	EP 0368651 A2	16-05-90					
7. <i>1</i>	EP 0486047 A2	20-05-92					
8. <i>1</i>	EP 0747974 A2	11-12-96					
9. <i>1</i>	EP 1065728 A2	03-01-01					
10. <i>gh</i>	GB 2332564 A	23-06-99	United Kingdom				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
<i>gh</i>	Olivares, J. et al.; "Solid-phase crystallization of amorphous SiGe films deposited by LPCVD on SiO <sub>2</sub> and glass," Thin Solid Films 337 (1999) pp. 51-54.

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EXAMINER <i>9</i>	DATE CONSIDERED <i>9/27/2004</i>
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SL	1.	5,389,398	02/14/95	Suzuki et al.	427	130	
	2.	5,698,771	12/16/97	Shields et al.	73	31.05	
	3.	6,228,181	05/08/01	Yamamoto et al.	148	33.5	
	4.	6,326,311	12/04/01	Ueda et al.	438	694	
	5.	6,455,892	09/24/02	Okuno et al.	257	328	
SL	6.	6,613,695	09/02/03	Pomarede et al.	438	767	

## FOREIGN PATENT DOCUMENTS

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							YES	NO

EXAMINER  
INITIAL

## OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

SL	7.	Ikoma et al., Growth of Si/3C-SiC/Si(100) heterostructures by pulsed supersonic free jets, Applied Physics Letters, Volume 75, No. 25, Pp. 3977-3979, December 1999					

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EXAMINER	<u>9</u>	DATE CONSIDERED	<u>9/27/2004</u>
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